Search Notes

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/777,465	LINN ET AL.	
	Examiner	Art Unit	
	Hwei-Siu C. Payer	3724	

	SEAR	CHED	
Class	Subclass	Date	Examiner
030	158	10-13-05	Payer
	159		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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